

<b>Notice of References Cited</b>	Application/Control No. 10/523,788		Applicant(s)/Patent Under Reexamination ITOU, DAISUKE	
	Examiner Jacob Y. Choi		Art Unit 2875	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,611,304	08-2003	Itoh et al.	349/65
*	B	US-6,309,081	10-2001	Furihata, Shinichi	362/634
*	C	US-6,419,369	07-2002	Itoh, Atsushi	362/26
*	D	US-5,537,296	07-1996	Kimura et al.	362/634
*	E	US-2002/0181225	12-2002	Matsushita, Hiromi	362/31
*	F	US-6,441,874	08-2002	Saito et al.	349/70
*	G	US-5,558,420	09-1996	Oki et al.	362/634
*	H	US-6,064,455	05-2000	Kim, Yong Gyu	349/113
*	I	US-6,343,868	02-2002	Itoh, Atsushi	362/609
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001-222903	08-2001	JAPAN	YOSHIDA TERUO	-----
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.